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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	37950
Number of Logic Elements/Cells	485760
Total RAM Bits	37969920
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1157-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7vx485t-2ffg1157i

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in the ISE® Design Suite 14.5 and Vivado® Design Suite 2013.1 as outlined in [Table 14](#).

Table 14: Virtex-7 T and XT FPGA Speed Specification Version By Device/Speed Grade

Version In:		Typical V _{CCINT}	Device
ISE 14.5	Vivado 2013.1	(Table 2)	
1.09	1.09	1.0V	XC7V585T, XC7VX485T
N/A	1.08	1.0V	XC7V2000T
1.08	1.08	1.0V	XC7VX330T, XC7VX415T, XC7VX550T, XC7VX690T, XC7VX980T
N/A	1.08	1.0V	XC7VX1140T

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Virtex-7 T and XT FPGAs.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-7 T and XT devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [AC Switching Characteristics, page 12](#). In each table, the I/O bank type is either High Performance (HP) or High Range (HR).

Table 17: Networking Applications Interface Performances

Description	I/O Bank Type	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	HR	710	710	625	Mb/s
	HP	710	710	625	Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	HR	1250	1250	950	Mb/s
	HP	1600	1400	1250	Mb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	HR	710	710	625	Mb/s
	HP	710	710	625	Mb/s
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	HR	1250	1250	950	Mb/s
	HP	1600	1400	1250	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

IOB Pad Input/Output/3-State

Table 19 (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than T_{IOTP} when the DCITERMDISABLE pin is used. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	
LVTTTL_S4	1.31	1.42	1.64	3.77	3.90	4.00	4.53	4.76	4.99	ns
LVTTTL_S8	1.31	1.42	1.64	3.50	3.64	3.73	4.26	4.50	4.72	ns
LVTTTL_S12	1.31	1.42	1.64	3.49	3.62	3.72	4.25	4.48	4.71	ns
LVTTTL_S16	1.31	1.42	1.64	3.03	3.17	3.26	3.79	4.03	4.25	ns
LVTTTL_S24	1.31	1.42	1.64	3.25	3.39	3.48	4.01	4.25	4.47	ns
LVTTTL_F4	1.31	1.42	1.64	3.22	3.36	3.45	3.98	4.22	4.44	ns
LVTTTL_F8	1.31	1.42	1.64	2.71	2.84	2.93	3.47	3.70	3.92	ns
LVTTTL_F12	1.31	1.42	1.64	2.69	2.82	2.92	3.45	3.68	3.91	ns
LVTTTL_F16	1.31	1.42	1.64	2.57	2.85	3.15	3.33	3.71	4.14	ns
LVTTTL_F24	1.31	1.42	1.64	2.41	2.64	2.89	3.17	3.50	3.88	ns
LVDS_25 ⁽¹⁾	0.64	0.68	0.80	1.36	1.47	1.55	2.12	2.33	2.54	ns
MINI_LVDS_25	0.68	0.70	0.79	1.36	1.47	1.55	2.12	2.33	2.54	ns
BLVDS_25 ⁽¹⁾	0.65	0.69	0.80	1.83	2.02	2.20	2.59	2.88	3.19	ns
RSDS_25 (point to point) ⁽¹⁾	0.63	0.68	0.79	1.36	1.48	1.55	2.12	2.34	2.54	ns
PPDS_25 ⁽¹⁾	0.65	0.69	0.80	1.36	1.49	1.58	2.12	2.35	2.57	ns
TMDS_33 ⁽¹⁾	0.72	0.76	0.86	1.43	1.54	1.60	2.19	2.40	2.59	ns
PCI33_3 ⁽¹⁾	1.28	1.41	1.65	2.71	3.08	3.52	3.47	3.94	4.51	ns
HSUL_12	0.63	0.64	0.71	1.77	1.90	2.00	2.53	2.76	2.99	ns
DIFF_HSUL_12	0.58	0.61	0.70	1.55	1.68	1.78	2.31	2.54	2.77	ns
HSTL_I_S	0.61	0.64	0.73	1.55	1.69	1.80	2.31	2.55	2.79	ns
HSTL_II_S	0.61	0.64	0.73	1.21	1.34	1.43	1.97	2.20	2.42	ns
HSTL_I_18_S	0.64	0.67	0.76	1.28	1.39	1.45	2.04	2.25	2.44	ns
HSTL_II_18_S	0.64	0.67	0.76	1.18	1.31	1.40	1.94	2.17	2.39	ns
DIFF_HSTL_I_S	0.63	0.67	0.77	1.42	1.54	1.61	2.18	2.40	2.60	ns
DIFF_HSTL_II_S	0.63	0.67	0.77	1.15	1.24	1.27	1.91	2.10	2.26	ns
DIFF_HSTL_I_18_S	0.65	0.69	0.78	1.27	1.38	1.43	2.03	2.24	2.42	ns
DIFF_HSTL_II_18_S	0.65	0.69	0.78	1.14	1.23	1.26	1.90	2.09	2.25	ns
HSTL_I_F	0.61	0.64	0.73	1.10	1.19	1.23	1.86	2.05	2.22	ns

Input/Output Logic Switching Characteristics

Table 22: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold					
T _{ICE1CK} /T _{ICKCE1}	CE1 pin setup/hold with respect to CLK	0.42/0.00	0.48/0.00	0.67/0.00	ns
T _{ISRCK} /T _{ICKSR}	SR pin setup/hold with respect to CLK	0.53/0.01	0.61/0.01	0.99/0.01	ns
T _{IDOCKE2} /T _{IOCKDE2}	D pin setup/hold with respect to CLK without delay (HP I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	ns
T _{IDOCKDE2} /T _{IOCKDDE2}	DDL _Y pin setup/hold with respect to CLK (using IDELAY) (HP I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	ns
T _{IDOCKE3} /T _{IOCKDE3}	D pin setup/hold with respect to CLK without delay (HR I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	ns
T _{IDOCKDE3} /T _{IOCKDDE3}	DDL _Y pin setup/hold with respect to CLK (using IDELAY) (HR I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	ns
Combinatorial					
T _{IDIE2}	D pin to O pin propagation delay, no delay (HP I/O banks only)	0.09	0.10	0.12	ns
T _{IDIDE2}	DDL _Y pin to O pin propagation delay (using IDELAY) (HP I/O banks only)	0.10	0.11	0.13	ns
T _{IDIE3}	D pin to O pin propagation delay, no delay (HR I/O banks only)	0.09	0.10	0.12	ns
T _{IDIDE3}	DDL _Y pin to O pin propagation delay (using IDELAY) (HR I/O banks only)	0.10	0.11	0.13	ns
Sequential Delays					
T _{IDLOE2}	D pin to Q1 pin using flip-flop as a latch without delay (HP I/O banks only)	0.36	0.39	0.45	ns
T _{IDLODE2}	DDL _Y pin to Q1 pin using flip-flop as a latch (using IDELAY) (HP I/O banks only)	0.36	0.39	0.45	ns
T _{IDLOE3}	D pin to Q1 pin using flip-flop as a latch without delay (HR I/O banks only)	0.36	0.39	0.45	ns
T _{IDLODE3}	DDL _Y pin to Q1 pin using flip-flop as a latch (using IDELAY) (HR I/O banks only)	0.36	0.39	0.45	ns
T _{ICKQ}	CLK to Q outputs	0.47	0.50	0.58	ns
T _{RQ_ILOGICE2}	SR pin to OQ/TQ out (HP I/O banks only)	0.84	0.94	1.16	ns
T _{GSRQ_ILOGICE2}	Global set/reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	ns
T _{RQ_ILOGICE3}	SR pin to OQ/TQ out (HR I/O banks only)	0.84	0.94	1.16	ns
T _{GSRQ_ILOGICE3}	Global set/reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	ns
Set/Reset					
T _{RPW_ILOGICE2}	Minimum pulse width, SR inputs (HP I/O banks only)	0.54	0.63	0.63	ns, Min
T _{RPW_ILOGICE3}	Minimum pulse width, SR inputs (HR I/O banks only)	0.54	0.63	0.63	ns, Min

Input/Output Delay Switching Characteristics

Table 26: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
IDELAYCTRL					
T _{DLYCCO_RDY}	Reset to ready for IDELAYCTRL	3.22	3.22	3.22	μs
F _{IDELAYCTRL_REF}	Attribute REFCLK frequency = 200.0 ⁽¹⁾	200	200	200	MHz
	Attribute REFCLK frequency = 300.0 ⁽¹⁾	300	300	N/A	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum reset pulse width	52.00	52.00	52.00	ns
IDELAY/ODELAY					
T _{IDELAYRESOLUTION}	IDELAY/ODELAY chain delay resolution	1/(32 x 2 x F _{REF})			ps
T _{IDELAYPAT_JIT} and T _{ODELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽³⁾	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽⁴⁾	±9	±9	±9	ps per tap
T _{IDELAY_CLK_MAX} / T _{ODELAY_CLK_MAX}	Maximum frequency of CLK input to IDELAY/ODELAY	800	800	710	MHz
T _{IDCCK_CE} / T _{IDCKC_CE}	CE pin setup/hold with respect to C for IDELAY	0.11/0.10	0.14/0.12	0.18/0.14	ns
T _{ODCCK_CE} / T _{ODCKC_CE}	CE pin setup/hold with respect to C for ODELAY	0.14/0.03	0.16/0.04	0.19/0.05	ns
T _{IDCCK_INC} / T _{IDCKC_INC}	INC pin setup/hold with respect to C for IDELAY	0.10/0.14	0.12/0.16	0.14/0.20	ns
T _{ODCCK_INC} / T _{ODCKC_INC}	INC pin setup/hold with respect to C for ODELAY	0.10/0.07	0.12/0.08	0.13/0.09	ns
T _{IDCCK_RST} / T _{IDCKC_RST}	RST pin setup/hold with respect to C for IDELAY	0.13/0.08	0.14/0.10	0.16/0.12	ns
T _{ODCCK_RST} / T _{ODCKC_RST}	RST pin setup/hold with respect to C for ODELAY	0.16/0.04	0.19/0.06	0.24/0.08	ns
T _{IDDO_IDATAIN}	Propagation delay through IDELAY	Note 5	Note 5	Note 5	ps
T _{ODDO_ODATAIN}	Propagation delay through ODELAY	Note 5	Note 5	Note 5	ps

Notes:

1. Average tap delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE.
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY/ODELAY tap setting. See the timing report for actual values.

Table 31: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Maximum Frequency					
F _{MAX_BRAM_WF_NC}	Block RAM (Write first and No change modes) When not in SDP RF mode	601.32	543.77	458.09	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (Read first, Performance mode) When in SDP RF mode but no address overlap between port A and port B	601.32	543.77	458.09	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (Read first, Delayed_write mode) When in SDP RF mode and there is possibility of overlap between port A and port B addresses	528.26	477.33	400.80	MHz
F _{MAX_CAS_WF_NC}	Block RAM Cascade (Write first, No change mode) When cascade but not in RF mode	551.27	493.83	408.00	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM Cascade (Read first, Performance mode) When in cascade with RF mode and no possibility of address overlap/one port is disabled	551.27	493.83	408.00	MHz
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B	478.24	427.35	350.88	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC	601.32	543.77	458.09	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	484.26	430.85	351.12	MHz

Notes:

1. The timing report shows all of these parameters as $T_{\text{RCKO_DO}}$.
2. $T_{\text{RCKO_DOR}}$ includes $T_{\text{RCKO_DOW}}$, $T_{\text{RCKO_DOPR}}$, and $T_{\text{RCKO_DOPW}}$ as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with $\text{DO_REG} = 0$.
4. $T_{\text{RCKO_DO}}$ includes $T_{\text{RCKO_DOP}}$ as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with $\text{DO_REG} = 1$.
6. $T_{\text{RCKO_FLAGS}}$ includes the following parameters: $T_{\text{RCKO_AEMPTY}}$, $T_{\text{RCKO_AFULL}}$, $T_{\text{RCKO_EMPTY}}$, $T_{\text{RCKO_FULL}}$, $T_{\text{RCKO_RDERR}}$, $T_{\text{RCKO_WRERR}}$.
7. $T_{\text{RCKO_POINTERS}}$ includes both $T_{\text{RCKO_RDCOUNT}}$ and $T_{\text{RCKO_WRCOUNT}}$.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. $T_{\text{RCO_FLAGS}}$ includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

DSP48E1 Switching Characteristics

Table 32: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup and Hold Times of Data/Control Pins to the Input Register Clock					
T _{DSPDCK_A_AREG} / T _{DSPCKD_A_AREG}	A input to A register CLK	0.24/0.12	0.27/0.14	0.31/0.16	ns
T _{DSPDCK_B_BREG} /T _{DSPCKD_B_BREG}	B input to B register CLK	0.28/0.13	0.32/0.14	0.39/0.15	ns
T _{DSPDCK_C_CREG} /T _{DSPCKD_C_CREG}	C input to C register CLK	0.15/0.15	0.17/0.17	0.20/0.20	ns
T _{DSPDCK_D_DREG} /T _{DSPCKD_D_DREG}	D input to D register CLK	0.21/0.19	0.27/0.22	0.35/0.26	ns
T _{DSPDCK_ACIN_AREG} /T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK	0.21/0.12	0.24/0.14	0.27/0.16	ns
T _{DSPDCK_BCIN_BREG} /T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK	0.22/0.13	0.25/0.14	0.30/0.15	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock					
T _{DSPDCK_{A,B}_MREG_MULT} /T _{DSPCKD_B_MREG_MULT}	{A, B,} input to M register CLK using multiplier	2.04/–0.01	2.34/–0.01	2.79/–0.01	ns
T _{DSPDCK_{A,B}_ADREG} / T _{DSPCKD_D_ADREG}	{A, D} input to AD register CLK	1.09/–0.02	1.25/–0.02	1.49/–0.02	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock					
T _{DSPDCK_{A,B}_PREG_MULT} /T _{DSPCKD_{A,B}_PREG_MULT}	{A, B,} input to P register CLK using multiplier	3.41/–0.24	3.90/–0.24	4.64/–0.24	ns
T _{DSPDCK_D_PREG_MULT} /T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier	3.33/–0.62	3.81/–0.62	4.53/–0.62	ns
T _{DSPDCK_{A,B}_PREG} /T _{DSPCKD_{A,B}_PREG}	A or B input to P register CLK not using multiplier	1.47/–0.24	1.68/–0.24	2.00/–0.24	ns
T _{DSPDCK_C_PREG} /T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier	1.30/–0.22	1.49/–0.22	1.78/–0.22	ns
T _{DSPDCK_PCIN_PREG} /T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK	1.12/–0.13	1.28/–0.13	1.52/–0.13	ns
Setup and Hold Times of the CE Pins					
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} /T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK	0.30/0.05	0.36/0.06	0.44/0.09	ns
T _{DSPDCK_CEC_CREG} /T _{DSPCKD_CEC_CREG}	CEC input to C register CLK	0.24/0.08	0.29/0.09	0.36/0.11	ns
T _{DSPDCK_CED_DREG} /T _{DSPCKD_CED_DREG}	CED input to D register CLK	0.31/–0.02	0.36/–0.02	0.44/–0.02	ns
T _{DSPDCK_CEM_MREG} /T _{DSPCKD_CEM_MREG}	CEM input to M register CLK	0.26/0.15	0.29/0.17	0.33/0.20	ns
T _{DSPDCK_CEP_PREG} / T _{DSPCKD_CEP_PREG}	CEP input to P register CLK	0.31/0.01	0.36/0.01	0.45/0.01	ns
Setup and Hold Times of the RST Pins					
T _{DSPDCK_{RSTA;RSTB}_{AREG;BREG}} /T _{DSPCKD_{RSTA;RSTB}_{AREG;BREG}}	{RSTA, RSTB} input to {A, B} register CLK	0.34/0.10	0.39/0.11	0.47/0.13	ns
T _{DSPDCK_RSTC_CREG} /T _{DSPCKD_RSTC_CREG}	RSTC input to C register CLK	0.06/0.22	0.07/0.24	0.08/0.26	ns
T _{DSPDCK_RSTD_DREG} /T _{DSPCKD_RSTD_DREG}	RSTD input to D register CLK	0.37/0.06	0.42/0.06	0.50/0.07	ns
T _{DSPDCK_RSTM_MREG} /T _{DSPCKD_RSTM_MREG}	RSTM input to M register CLK	0.18/0.18	0.20/0.21	0.23/0.24	ns
T _{DSPDCK_RSTP_PREG} /T _{DSPCKD_RSTP_PREG}	RSTP input to P register CLK	0.24/0.01	0.26/0.01	0.30/0.01	ns
Combinatorial Delays from Input Pins to Output Pins					
T _{DSPDO_A_CARRYOUT_MULT}	A input to CARRYOUT output using multiplier	3.21	3.69	4.39	ns
T _{DSPDO_D_P_MULT}	D input to P output using multiplier	3.15	3.61	4.30	ns

Table 32: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
$T_{\text{DSPDO_A_P}}$	A input to P output not using multiplier	1.30	1.48	1.76	ns
$T_{\text{DSPDO_C_P}}$	C input to P output	1.13	1.30	1.55	ns
Combinatorial Delays from Input Pins to Cascading Output Pins					
$T_{\text{DSPDO_}\{A; B\}_ \{ACOUT; BCOUT\}}$	{A, B} input to {ACOUT, BCOUT} output	0.47	0.53	0.63	ns
$T_{\text{DSPDO_}\{A, B\}_ \text{CARRYCASCOUT_MULT}}$	{A, B} input to CARRYCASCOUT output using multiplier	3.44	3.94	4.69	ns
$T_{\text{DSPDO_D_CARRYCASCOUT_MULT}}$	D input to CARRYCASCOUT output using multiplier	3.36	3.85	4.58	ns
$T_{\text{DSPDO_}\{A, B\}_ \text{CARRYCASCOUT}}$	{A, B} input to CARRYCASCOUT output not using multiplier	1.50	1.72	2.04	ns
$T_{\text{DSPDO_C_CARRYCASCOUT}}$	C input to CARRYCASCOUT output	1.34	1.53	1.83	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins					
$T_{\text{DSPDO_ACIN_P_MULT}}$	ACIN input to P output using multiplier	3.09	3.55	4.24	ns
$T_{\text{DSPDO_ACIN_P}}$	ACIN input to P output not using multiplier	1.16	1.33	1.59	ns
$T_{\text{DSPDO_ACIN_ACOUT}}$	ACIN input to ACOUT output	0.32	0.37	0.45	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT_MULT}}$	ACIN input to CARRYCASCOUT output using multiplier	3.30	3.79	4.52	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT}}$	ACIN input to CARRYCASCOUT output not using multiplier	1.37	1.57	1.87	ns
$T_{\text{DSPDO_PCIN_P}}$	PCIN input to P output	0.94	1.08	1.29	ns
$T_{\text{DSPDO_PCIN_CARRYCASCOUT}}$	PCIN input to CARRYCASCOUT output	1.15	1.32	1.57	ns
Clock to Outs from Output Register Clock to Output Pins					
$T_{\text{DSPCKO_P_PREG}}$	CLK PREG to P output	0.33	0.35	0.39	ns
$T_{\text{DSPCKO_CARRYCASCOUT_PREG}}$	CLK PREG to CARRYCASCOUT output	0.44	0.50	0.59	ns
Clock to Outs from Pipeline Register Clock to Output Pins					
$T_{\text{DSPCKO_P_MREG}}$	CLK MREG to P output	1.42	1.64	1.96	ns
$T_{\text{DSPCKO_CARRYCASCOUT_MREG}}$	CLK MREG to CARRYCASCOUT output	1.63	1.87	2.24	ns
$T_{\text{DSPCKO_P_ADREG_MULT}}$	CLK ADREG to P output using multiplier	2.30	2.63	3.13	ns
$T_{\text{DSPCKO_CARRYCASCOUT_ADREG_MULT}}$	CLK ADREG to CARRYCASCOUT output using multiplier	2.51	2.87	3.41	ns
Clock to Outs from Input Register Clock to Output Pins					
$T_{\text{DSPCKO_P_AREG_MULT}}$	CLK AREG to P output using multiplier	3.34	3.83	4.55	ns
$T_{\text{DSPCKO_P_BREG}}$	CLK BREG to P output not using multiplier	1.39	1.59	1.88	ns
$T_{\text{DSPCKO_P_CREG}}$	CLK CREG to P output not using multiplier	1.43	1.64	1.95	ns
$T_{\text{DSPCKO_P_DREG_MULT}}$	CLK DREG to P output using multiplier	3.32	3.80	4.51	ns

Clock Buffers and Networks

Table 33: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
$T_{BCCCK_CE}/T_{BCCCK_CE}^{(1)}$	CE pins setup/hold	0.12/0.30	0.14/0.38	0.26/0.38	ns
$T_{BCCCK_S}/T_{BCCCK_S}^{(1)}$	S pins setup/hold	0.12/0.30	0.14/0.38	0.26/0.38	ns
$T_{BCKO_O}^{(2)}$	BUFGCTRL delay from I/O to O	0.08	0.10	0.12	ns
Maximum Frequency					
F_{MAX_BUFG}	Global clock tree (BUFG)	741.00	710.00	625.00	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCCK_S} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BCKO_O} (BUFG delay from I/O to O) values are the same as T_{BCKO_O} values.

Table 34: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T_{BIOCKO_O}	Clock to out delay from I to O	1.04	1.14	1.32	ns
Maximum Frequency					
F_{MAX_BUFIO}	I/O clock tree (BUFIO)	800.00	800.00	710.00	MHz

Table 35: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T_{BRCKO_O}	Clock to out delay from I to O	0.60	0.65	0.77	ns
$T_{BRCKO_O_BYP}$	Clock to out delay from I to O with Divide Bypass attribute set	0.30	0.32	0.38	ns
T_{BRDO_O}	Propagation delay from CLR to O	0.71	0.75	0.96	ns
Maximum Frequency					
$F_{MAX_BUFR}^{(1)}$	Regional clock tree (BUFR)	600.00	540.00	450.00	MHz

Notes:

1. The maximum input frequency to the BUFR and BUFMR is the BUFIO F_{MAX} frequency.

Table 36: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T_{BHCKO_O}	BUFH delay from I to O	0.10	0.11	0.13	ns
$T_{BHCKCK_CE}/T_{BHCKCK_CE}$	CE pin setup and hold	0.20/0.16	0.23/0.20	0.38/0.21	ns
Maximum Frequency					
F_{MAX_BUFH}	Horizontal clock buffer (BUFH)	741.00	710.00	625.00	MHz

Table 38: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
MMCM_T _{LOCKMAX}	MMCM maximum Lock Time	100	100	100	μs
MMCM_F _{OUTMAX}	MMCM maximum output frequency	1066.00	933.00	800.00	MHz
MMCM_F _{OUTMIN}	MMCM minimum output frequency ⁽⁵⁾⁽⁶⁾	4.69	4.69	4.69	MHz
MMCM_T _{EXTFDVAR}	External clock feedback variation	< 20% of clock input period or 1 ns Max			
MMCM_RST _{MINPULSE}	Minimum reset pulse width	5.00	5.00	5.00	ns
MMCM_F _{PFDMAX}	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	MHz
MMCM_F _{PFDMIN}	Minimum frequency at the phase frequency detector	10.00	10.00	10.00	MHz
MMCM_T _{FBDELAY}	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle			
MMCM Switching Characteristics Setup and Hold					
T _{MMCMDCK_PSEN} / T _{MMCMCKD_PSEN}	Setup and hold of phase-shift enable	1.04/0.00	1.04/0.00	1.04/0.00	ns
T _{MMCMDCK_PSINCDEC} / T _{MMCMCKD_PSINCDEC}	Setup and hold of phase-shift increment/decrement	1.04/0.00	1.04/0.00	1.04/0.00	ns
T _{MMCMCKO_PSDONE}	Phase shift clock-to-out of PSDONE	0.59	0.68	0.81	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK					
T _{MMCMDCK_DADDR} / T _{MMCMCKD_DADDR}	DADDR setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T _{MMCMDCK_DI} /T _{MMCMCKD_DI}	DI setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T _{MMCMDCK_DEN} /T _{MMCMCKD_DEN}	DEN setup/hold	1.76/0.00	1.97/0.00	2.29/0.00	ns, Min
T _{MMCMDCK_DWE} /T _{MMCMCKD_DWE}	DWE setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T _{MMCMCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	MHz, Max

Notes:

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.
6. When CLKOUT4_CASCADE = TRUE, MMCM_F_{OUTMIN} is 0.036 MHz.

PLL Switching Characteristics

Table 39: PLL Specification

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
PLL_F _{INMAX}	Maximum input clock frequency	1066.00	933.00	800.00	MHz
PLL_F _{INMIN}	Minimum input clock frequency	19.00	19.00	19.00	MHz
PLL_F _{INJITTER}	Maximum input clock period jitter	< 20% of clock input period or 1 ns Max			
PLL_F _{INDUTY}	Allowable input duty cycle: 19—49 MHz	25	25	25	%
	Allowable input duty cycle: 50—199 MHz	30	30	30	%
	Allowable input duty cycle: 200—399 MHz	35	35	35	%
	Allowable input duty cycle: 400—499 MHz	40	40	40	%
	Allowable input duty cycle: >500 MHz	45	45	45	%
PLL_F _{VCOMIN}	Minimum PLL VCO frequency	800.00	800.00	800.00	MHz
PLL_F _{VCOMAX}	Maximum PLL VCO frequency	2133.00	1866.00	1600.00	MHz
PLL_F _{BANDWIDTH}	Low PLL bandwidth at typical ⁽¹⁾	1.00	1.00	1.00	MHz
	High PLL bandwidth at typical ⁽¹⁾	4.00	4.00	4.00	MHz
PLL_T _{STATPHAOFFSET}	Static phase offset of the PLL outputs ⁽²⁾	0.12	0.12	0.12	ns
PLL_T _{OUTJITTER}	PLL output jitter	Note 3			
PLL_T _{OUTDUTY}	PLL output clock duty cycle precision ⁽⁴⁾	0.20	0.20	0.20	ns
PLL_T _{LOCKMAX}	PLL maximum lock time	100	100	100	μs
PLL_F _{OUTMAX}	PLL maximum output frequency	1066.00	933.00	800.00	MHz
PLL_F _{OUTMIN}	PLL minimum output frequency ⁽⁵⁾	6.25	6.25	6.25	MHz
PLL_T _{EXTFDVAR}	External clock feedback variation	< 20% of clock input period or 1 ns Max			
PLL_RST _{MINPULSE}	Minimum reset pulse width	5.00	5.00	5.00	ns
PLL_F _{PFDMAX}	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	MHz
PLL_F _{PFDMIN}	Minimum frequency at the phase frequency detector	19.00	19.00	19.00	MHz
PLL_T _{FBDELAY}	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle			
Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK					
T _{PLLDCK_DADDR} /T _{PLLCKD_DADDR}	DADDR setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T _{PLLDCK_DI} /T _{PLLCKD_DI}	DI setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T _{PLLDCK_DEN} /T _{PLLCKD_DEN}	DEN setup/hold	1.76/0.00	1.97/0.00	2.29/0.00	ns, Min
T _{PLLDCK_DWE} /T _{PLLCKD_DWE}	DWE setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T _{PLLCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	MHz, Max

Notes:

- The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
- The static offset is measured between any PLL outputs with identical phase.
- Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
- Includes global clock buffer.
- Calculated as F_{VCO}/128 assuming output duty cycle is 50%.

GTX Transceiver Specifications

GTX Transceiver DC Input and Output Levels

Table 51 summarizes the DC specifications of the GTX transceivers in Virtex-7 T and XT FPGAs. Consult the *7 Series FPGAs GTX/GTH Transceiver User Guide* (UG476) for further details.

Table 51: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV _{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	–	–	1000	mV
V _{CMOUTDC}	DC common mode output voltage.	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R _{OUT}	Differential output resistance		–	100	–	Ω
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	12	ps
DV _{PPIN}	Differential peak-to-peak input voltage (external AC coupled)	>10.3125 Gb/s	150	–	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	–	1250	mV
		≤ 6.6 Gb/s	150	–	2000	mV
V _{IN}	Absolute input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	–200	–	$V_{MGTAVTT}$	mV
V _{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	–	$2/3 V_{MGTAVTT}$	–	mV
R _{IN}	Differential input resistance		–	100	–	Ω
C _{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

- The output swing and preemphasis levels are programmable using the attributes discussed in the *7 Series FPGAs GTX/GTH Transceiver User Guide* (UG476), and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

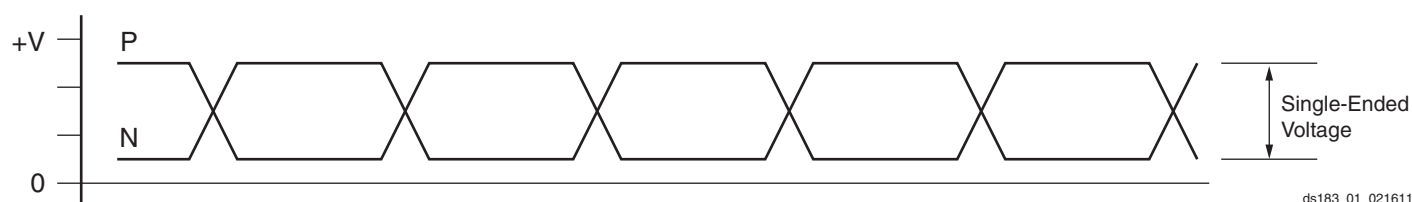


Figure 1: Single-Ended Peak-to-Peak Voltage

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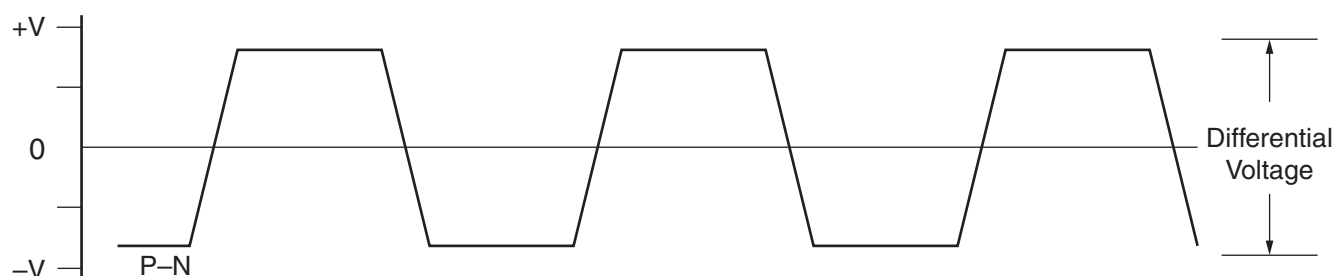


Figure 2: Differential Peak-to-Peak Voltage

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Table 52 summarizes the DC specifications of the clock input of the GTX transceiver. Consult the *7 Series FPGAs GTX/GTH Transceiver User Guide* ([UG476](#)) for further details.

Table 52: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V _{IDIFF}	Differential peak-to-peak input voltage	250	–	2000	mV
R _{IN}	Differential input resistance	–	100	–	Ω
C _{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTX Transceiver Switching Characteristics

Consult the *7 Series FPGAs GTX/GTH Transceiver User Guide* ([UG476](#)) for further information.

Table 53: GTX Transceiver Performance

Symbol	Description	Output Divider	Speed Grade			Units
			-3/-2G	-2/-2L	-1 ⁽¹⁾	
F _{GTXMAX} ⁽²⁾	Maximum GTX transceiver data rate		12.5	10.3125	8.0	Gb/s
F _{GTXMIN} ⁽²⁾	Minimum GTX transceiver data rate		0.500	0.500	0.500	Gb/s
F _{GTXCRANGE}	CPLL line rate range	1	3.2–6.6			Gb/s
		2	1.6–3.3			Gb/s
		4	0.8–1.65			Gb/s
		8	0.5–0.825			Gb/s
		16	N/A			Gb/s
F _{GTXQRANGE1}	QPLL line rate range 1	1	5.93–8.0	5.93–8.0	5.93–8.0	Gb/s
		2	2.965–4.0	2.965–4.0	2.965–4.0	Gb/s
		4	1.4825–2.0	1.4825–2.0	1.4825–2.0	Gb/s
		8	0.74125–1.0	0.74125–1.0	0.74125–1.0	Gb/s
		16	N/A	N/A	N/A	Gb/s
F _{GTXQRANGE2}	QPLL line rate range 2 ⁽³⁾	1	9.8–12.5	9.8–10.3125	N/A	Gb/s
		2	4.9–6.25	4.9–5.15625	N/A	Gb/s
		4	2.45–3.125	2.45–2.578125	N/A	Gb/s
		8	1.225–1.5625	1.225–1.2890625	N/A	Gb/s
		16	0.6125–0.78125	0.6125–0.64453125	N/A	Gb/s
F _{GCPLLRANGE}	GTX transceiver CPLL frequency range		1.6–3.3	1.6–3.3	1.6–3.3	GHz
F _{GQPLLRange1}	GTX transceiver QPLL frequency range 1		5.93–8.0	5.93–8.0	5.93–8.0	GHz
F _{GQPLLRange2}	GTX transceiver QPLL frequency range 2		9.8–12.5	9.8–10.3125	N/A	GHz

Notes:

- The -1 speed grade requires a 4-byte internal data width for operation above 5.0 Gb/s. A -1 speed grade with V_{CCINT} = 0.9V, as described in the *Lowering Power using the Voltage Identification Bit* application note ([XAPP555](#)), requires a 4-byte internal data width for operation above 3.8 Gb/s.
- Data rates between 8.0 Gb/s and 9.8 Gb/s are not available.
- For QPLL line rate range 2, the maximum line rate with the divider N set to 66 is 10.3125Gb/s.

Table 54: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3/-2G	-2/-2L	-1	
F _{GTXDRPCLK}	GTXDRPCLK maximum frequency	175.01	175.01	156.25	MHz

GTX Transceiver Protocol Jitter Characteristics

For Table 60 through Table 65, the 7 Series FPGAs GTX/GTH Transceiver User Guide ([UG476](#)) contains recommended settings for optimal usage of protocol specific characteristics.

Table 60: Gigabit Ethernet Protocol Characteristics (GTX Transceivers)

Description	Line Rate (Mb/s)	Min	Max	Units
Gigabit Ethernet Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	1250	–	0.24	UI
Gigabit Ethernet Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	1250	0.749	–	UI

Table 61: XAUI Protocol Characteristics (GTX Transceivers)

Description	Line Rate (Mb/s)	Min	Max	Units
XAUI Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	3125	–	0.35	UI
XAUI Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	3125	0.65	–	UI

Table 62: PCI Express Protocol Characteristics (GTX Transceivers)⁽¹⁾

Standard	Description		Line Rate (Mb/s)	Min	Max	Units
PCI Express Transmitter Jitter Generation						
PCI Express Gen 1	Total transmitter jitter		2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter		5000	–	0.25	UI
PCI Express Gen 3 ⁽²⁾	Total transmitter jitter uncorrelated		8000	–	31.25	ps
	Deterministic transmitter jitter uncorrelated			–	12	ps
PCI Express Receiver High Frequency Jitter Tolerance						
PCI Express Gen 1	Total receiver jitter tolerance		2500	0.65	–	UI
PCI Express Gen 2 ⁽³⁾	Receiver inherent timing error		5000	0.40	–	UI
	Receiver inherent deterministic timing error			0.30	–	UI
PCI Express Gen 3 ⁽²⁾	Receiver sinusoidal jitter tolerance	0.03 MHz–1.0 MHz	8000	1.00	–	UI
		1.0 MHz–10 MHz		Note 4	–	UI
		10 MHz–100 MHz		0.10	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. PCI-SIG 3.0 certification and compliance test boards are currently not available.
3. Using common REFCLK.
4. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20dB/decade.

Table 63: CEI-6G and CEI-11G Protocol Characteristics (GTX Transceivers)

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter ⁽¹⁾	4976–6375	CEI-6G-SR	–	0.3	UI
		CEI-6G-LR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽¹⁾	4976–6375	CEI-6G-SR	0.6	–	UI
		CEI-6G-LR	0.95	–	UI
CEI-11G Transmitter Jitter Generation					
Total transmitter jitter ⁽²⁾	9950–11100	CEI-11G-SR	–	0.3	UI
		CEI-11G-LR/MR	–	0.3	UI
CEI-11G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽²⁾	9950–11100	CEI-11G-SR	0.65	–	UI
		CEI-11G-MR	0.65	–	UI
		CEI-11G-LR	0.825	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.
2. Tested at line rate of 9950 Mb/s using 155.46875 MHz reference clock and 11100 Mb/s using 173.4375 MHz reference clock.

Table 64: SFP+ Protocol Characteristics (GTX Transceivers)

Description	Line Rate (Mb/s)	Min	Max	Units
SFP+ Transmitter Jitter Generation				
Total transmitter jitter	9830.40 ⁽¹⁾	–	0.28	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			
SFP+ Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	9830.40 ⁽¹⁾	0.7	–	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			

Notes:

1. Line rated used for CPRI over SFP+ applications.

Table 78: CEI-6G and CEI-11G Protocol Characteristics (GTH Transceivers)

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter ⁽¹⁾	4976–6375	CEI-6G-SR	–	0.3	UI
		CEI-6G-LR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽¹⁾	4976–6375	CEI-6G-SR	0.6	–	UI
		CEI-6G-LR	0.95	–	UI
CEI-11G Transmitter Jitter Generation					
Total transmitter jitter ⁽²⁾	9950–11100	CEI-11G-SR	–	0.3	UI
		CEI-11G-LR/MR	–	0.3	UI
CEI-11G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽²⁾	9950–11100	CEI-11G-SR	0.65	–	UI
		CEI-11G-MR	0.65	–	UI
		CEI-11G-LR	0.825	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.
2. Tested at line rate of 9950 Mb/s using 155.46875 MHz reference clock and 11100 Mb/s using 173.4375 MHz reference clock.

Table 79: SFP+ Protocol Characteristics (GTH Transceivers)

Description	Line Rate (Mb/s)	Min	Max	Units
SFP+ Transmitter Jitter Generation				
Total transmitter jitter	9830.40 ⁽¹⁾	–	0.28	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			
SFP+ Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	9830.40 ⁽¹⁾	0.7	–	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			

Notes:

1. Line rated used for CPRI over SFP+ applications.

XADC Specifications

Table 82: XADC Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
V _{CCADC} = 1.8V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 26 MHz, T _j = −40°C to 100°C, Typical values at T _j =+40°C						
ADC Accuracy ⁽¹⁾						
Resolution			12	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±3	LSBs
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	LSBs
Offset Error		Offset calibration enabled	–	–	±6	LSBs
Gain Error		Gain calibration disabled	–	–	±0.5	%
Offset Matching		Offset calibration enabled	–	–	4	LSBs
Gain Matching		Gain calibration disabled	–	–	0.3	%
Sample Rate			0.1	–	1	MS/s
Signal to Noise Ratio ⁽²⁾	SNR	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	60	–	–	dB
RMS Code Noise		External 1.25V reference	–	–	2	LSBs
		On-chip reference	–	3	–	LSBs
Total Harmonic Distortion ⁽²⁾	THD	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	–	70	–	dB
ADC Accuracy at Extended Temperatures (−55°C to 125°C)						
Resolution			10	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±1	LSB (at 10 bits)
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	
Analog Inputs ⁽³⁾						
ADC Input Ranges		Unipolar operation	0	–	1	V
		Bipolar operation	−0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum External Channel Input Ranges		Adjacent channels set within these ranges should not corrupt measurements on adjacent channels	−0.1	–	V _{CCADC}	V
Auxiliary Channel Full Resolution Bandwidth	FRBW		250	–	–	KHz
On-Chip Sensors						
Temperature Sensor Error		T _j = −40°C to 100°C.	–	–	±4	°C
		T _j = −55°C to +125°C	–	–	±6	°C
Supply Sensor Error		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −40°C to +100°C	–	–	±1	%
		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −55°C to +125°C	–	–	±2	%
Conversion Rate ⁽⁴⁾						
Conversion Time - Continuous	t _{CONV}	Number of ADCCLK cycles	26	–	32	cycle
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	cycle
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	250	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	26	MHz
DCLK Duty Cycle			40	–	60	%

Table 82: XADC Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
XADC Reference⁽⁵⁾						
External Reference	V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
On-Chip Reference		Ground V_{REFP} pin to AGND, $T_j = -40^{\circ}\text{C}$ to 100°C	1.2375	1.25	1.2625	V

Notes:

- Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
- Only specified for new BitGen option XADCEnhancedLinearity = ON.
- For a detailed description, see the ADC chapter in the *7 Series FPGAs and Zynq-7000 AP SoC XADC Dual 12-Bit 1 MSPS Analog-to-Digital Converter* (UG480).
- For a detailed description, see the Timing chapter in the *7 Series FPGAs and Zynq-7000 AP SoC XADC Dual 12-Bit 1 MSPS Analog-to-Digital Converter* (UG480).
- Any variation in the reference voltage from the nominal $V_{REFP} = 1.25\text{V}$ and $V_{REFN} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by $\pm 4\%$ is permitted. On-chip reference variation is $\pm 1\%$.

Configuration Switching Characteristics

Table 83: Configuration Switching Characteristics

Symbol	Description	Virtex-7 T and XT Devices	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program latency		5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on reset (50ms ramp rate time)		10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1ms ramp rate time)		10/35	10/35	10/35	ms, Min/Max
T _{PROGRAM}	Program pulse width		250	250	250	ns, Min
CCLK Output (Master Mode)						
T _{ICCK}	Master CCLK output delay		150	150	150	ns, Min
T _{MCCKL}	Master CCLK clock Low time duty cycle		40/60	40/60	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle		40/60	40/60	40/60	%, Min/Max
F _{MCCK}	Master CCLK frequency		100	100	100	MHz, Max
	Master CCLK frequency for AES encrypted x16		50	50	50	MHz, Max
F _{MCCK_START}	Master CCLK frequency at start of configuration		3	3	3	MHz, Typ
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK.		±50	±50	±50	%, Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time		2.5	2.5	2.5	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time		2.5	2.5	2.5	ns, Min
F _{SCCK}	Slave CCLK frequency		100	100	100	MHz, Max
EMCCLK Input (Master Mode)						
T _{EMCCKL}	External master CCLK Low time		2.5	2.5	2.5	ns, Min
T _{EMCCKH}	External master CCLK High time		2.5	2.5	2.5	ns, Min
F _{EMCCK}	External master CCLK frequency		100	100	100	MHz, Max
Internal Configuration Access Port						
F _{ICAPCK}	Internal configuration access port (ICAPE2)		100.00	100.00	100.00	MHz, Max

Table 83: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Virtex-7 T and XT Devices	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
Master/Slave Serial Mode Programming Switching						
T _{DCC} /T _{CCKD}	DIN setup/hold		4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
T _{CCO}	DOUT clock to out		8.0	8.0	8.0	ns, Max
SelectMAP Mode Programming Switching						
T _{SMDCC} /T _{SMCCKD}	D[31:00] setup/hold		4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
T _{SMCSCCK} /T _{SMCCKCS}	CSI_B setup/hold		4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
T _{SMWCCK} /T _{SMCKKW}	RDWR_B setup/hold		10.0/0.0	10.0/0.0	10.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)		7.0	7.0	7.0	ns, Max
T _{SMCO}	D[31:00] clock to out in readback		8.0	8.0	8.0	ns, Max
F _{RBCK}	Readback frequency	SLR-based	70	70	70	MHz, Max
		All other devices	100	100	100	MHz, Max
Boundary-Scan Port Timing Specifications						
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI setup/hold	SLR-based	9.0/2.0	9.0/2.0	9.0/2.0	ns, Min
		All other devices	3.0/2.0	3.0/2.0	3.0/2.0	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output	SLR-based	17	17	17	ns, Max
		All other devices	7.0	7.0	7.0	ns, Max
F _{TCK}	TCK frequency	SLR-based	20	20	20	MHz, Max
		All other devices	66	66	66	MHz, Max
BPI Master Flash Mode Programming Switching						
T _{BPICCO} ⁽²⁾	A[28:00], RS[1:0], FCS_B, FOE_B, FWE_B, ADV_B clock to out		8.5	8.5	8.5	ns, Max
T _{BPIDCC} /T _{BPICCD}	D[15:00] setup/hold		4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
SPI Master Flash Mode Programming Switching						
T _{SPIDCC} /T _{SPICCD}	D[03:00] setup/hold		3.0/0.0	3.0/0.0	3.0/0.0	ns, Min
T _{SPICCM}	MOSI clock to out		8.0	8.0	8.0	ns, Max
T _{SPICCF}	FCS_B clock to out		8.0	8.0	8.0	ns, Max

Notes:

1. To support longer delays in configuration, use the design solutions described in the *7 Series FPGA Configuration User Guide* ([UG470](#)).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.

eFUSE Programming Conditions

Table 84 lists the programming conditions specifically for eFUSE. For more information, see the *7 Series FPGA Configuration User Guide* ([UG470](#)).

Table 84: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
I_{FS}	V_{CCAUX} supply current	–	–	115	mA
t_j	Temperature range	15	–	125	°C

Notes:

1. The FPGA must not be configured during eFUSE programming.

Date	Version	Description
03/27/2013	1.13	In Table 7 , added values for the XC7VX330T and XC7VX415T devices. Revised Table 15 and Table 16 to include production release of the XC7VX330T and XC7VX415T. In Table 18 , updated the table title, LPDDR2 values, and removed Note 3. Removed Note 2: <i>For QPLL line rate, the maximum line rate with the divider N set to 66 is 10.3125 Gb/s</i> from Table 68 .
04/17/2013	1.14	Updated the AC Switching Characteristics section with production release changes to Table 15 and Table 16 for XC7VX550T for all speed specifications. In Table 1 , revised V_{IN} (I/O input voltage) to match values in Table 4 and Table 5 , and combined Note 4 with old Note 5 and then added new Note 5 . Revised V_{IN} description and added Note 8 in Table 2 . Updated first 3 rows in Table 4 and Table 5 . Updated values and added new values to Table 7 . Also revised PCI33_3 voltage minimum in Table 10 to match values in Table 1 , Table 4 , and Table 5 . Added Note 1 to Table 12 and Table 13 . Throughout the data sheet (Table 29 , Table 30 , and Table 45) removed the obvious note "A Zero "0" Hold Time listing indicates no hold time or a negative hold time." Updated and clarified USRCLK data in Table 57 and Table 72 .

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